



4/8/2009

**RELIABILITY MONITOR REPORT
FOR**

Chartered 0.35 μ m Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS2155	DS26303	DS26900	DS3150	DS33R41
--------	---------	---------	--------	---------

The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 19623** **FITS: 5.8**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2007 and 6/30/2008 .

Process Information:

Process Description: Chartered 0.35µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0716	DS26900	125C, 3.5 VOLTS	1000 HRS	45	0	QN077106BA-NPI
HIGH TEMP OP LIFE	0735	DS3150	125C, 3.5 VOLTS	1000 HRS	77	0	QN072457AB-NPI
HIGH TEMP OP LIFE	0811	DS26303	125C, 3.5 VOLTS	1000 HRS	45	0	QN080344BB-NPI
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0708	DS33R41	-40C TO +125C	1000 CYS	77	0	QK562042AJA
TEMP CYCLE, 5' RAMP, 10' DWELL	0729	DS2155	-55C TO 125C	1000 CYS	77	0	QC078266AB
Total:						0	

FAILURE RATE: **MTTF (YRS): 19623** **FITS: 5.8**